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# **Texas Instruments Enhanced Plastic Products Reliability Report**

(Subject To Attached Disclaimers)

Device Type/Device Family: ISO7221HD
Package Type: 8/D
Wafer Fabrication Facility: DFAB
Assembly/Test Facility: Hana
Compiled: 03/12

### **Biased Life Test**

Test Method: JESD22-A108

Test Condition: 175C/1000 hours or equivalent 45/0 Minimum Sample

Sample Size: 45 Rejects: 0

## Package Sequence Test

| <u>Description</u>                    | <b>Condition</b>                                                      | Referenced Method                               | Lot/Sample   | Rejects |
|---------------------------------------|-----------------------------------------------------------------------|-------------------------------------------------|--------------|---------|
| Preconditioning                       |                                                                       | QSS009-142<br>JEDEC Std. 22 Method<br>A112/A113 | 3/45         | 0       |
| CSAM/TSAM<br>Exposed pad devices only | No Delamination                                                       |                                                 | 3/45         | 0       |
| Storage Bake                          | 2000hr @ Data Sheet<br>Operating Temperature                          |                                                 | 3/45         | N/A     |
| Temperature Cycle                     | -65°C to +150°C non-biased for 500 cycles or equivalent JESD22-A104-A |                                                 | 3/45         | N/A     |
| Electrical Test                       | Per Data Sheet with Additional<br>Pin to Pin Leakage Testing          |                                                 |              | 0       |
| CSAM                                  | No Delamination on<br>Lead or Die                                     |                                                 |              | 0       |
| TSAM<br>Exposed pad devices only      | 50% Maximum Mount Pad Delamination                                    |                                                 | 3/5          | 0       |
| Decap/Bond Pull                       | Wirebond Packages Only                                                |                                                 | 3/5-15 Wires | 0       |
| Decap/Bond Shear                      | Wirebond Packages Only                                                | ASTM F-459                                      | 3/5-15 Wires | 0       |
| Cross Section                         | Through ball bond or flip chip bump Examine for bond Integrit         |                                                 | 3/1          | 0       |

## **Additional Qualification Testing**

The subject Enhanced Plastic device, device family, and/or package family have passed Texas Instruments product qualification as follows:

| <u>Description</u>                     | <u>Condition</u>                                        | Referenced Method                                 | Sample Size                   |   |
|----------------------------------------|---------------------------------------------------------|---------------------------------------------------|-------------------------------|---|
| Electrical Characterization            | TI Data Sheet                                           | N/A                                               | 30 Units                      |   |
| Electrostatic Discharge<br>Sensitivity | HBM<br>MM<br>CDM                                        | EIA/JESD22-A114<br>EIA/JESD22-A115<br>JESD22-C101 | 3 Units/voltage<br>N/A<br>N/A |   |
| Latch-up                               | Per Technology                                          | EIA/JESD78                                        | 6/0                           |   |
| Physical Dimensions                    | TI Data Sheet                                           | EIA/JESD22- B100                                  | 15/0                          |   |
| Thermal Impedance                      | Theta-JA on board                                       | EIA/JESD51                                        | Per Pin-Package               |   |
| Bias Life Test                         | 125°C / 1000 hours or<br>equivalent                     | JESD22-A108                                       | 77/0                          |   |
| Biased Humidity                        | 85°C / 85% / 1000 hours                                 | JESD22-A101                                       | 77/0                          | * |
| or<br>HAST                             | or<br>130°C / 85% / 96 hours                            | JESD22-A110                                       |                               |   |
| Autoclave<br>or                        | 121°C @ 2 atm / 96 hours                                | JESD22-A102                                       | 77/0                          | * |
| Unbiased HAST                          | 130°C / 85% / 96 hours                                  | JESD22-A110                                       |                               |   |
| Temperature Cycle                      | -65°C to +150°C non-biased for 500 cycles or equivalent | JESD22-A104                                       | 77/0                          | * |
| Solderability                          | Condition A (steam age for 8 hours)                     | ANSI/J-STD-002-92                                 | 22/0                          |   |
| Bond Strength                          | -                                                       | ASTM F-459                                        | 30/0                          |   |
| Moisture Sensitivity                   | Surface Mount Only                                      | J-STD-020-A                                       | 12/0                          |   |

<sup>\*</sup> Preconditioning per JEDEC Std. 22, Method A112/A113

### **Suplemental Device Characteristics**

Master Die: BLBFI7221CLBC/BLBFI7221Cf
Wafer Fab: DFAB
Fab Process: DFAB
Assembly Site: Hana
Pin/Package Type: 8/D
Lead Composition: Copper Alloy

Fab Technology: LBC4HVC Lead Composition: Copper Alice Lead Composition: Copper Alice Lead Finish: NiPdAu

Die Revision: BLBFI7221CLBC/BLBFI7221Cl Packaged Die Thickness: SID#400154 (EIS#6499133)

Passivation: 11.5K Nitride MSL Level: MSL1/260

Metal 1: 3kA TiW/4.5kA AlSiCu.5 Metal 4: 6um Cu/3um Ni/0.3um Pd (HBL

 Metal 2: 3kA TiW/4.5kA AlSiCu.5
 Metal 5: N/A

 Metal 3: 3kA TiW/6kA AlSiCu.5
 Metal 6: N/A

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